


<b><i>Search Notes</i></b>  	<b>Application/Control No.</b>  10617616	<b>Applicant(s)/Patent Under Reexamination</b>  RAJU ET AL.
	<b>Examiner</b>  SUN JAE Y LOEWE	<b>Art Unit</b>  1626

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
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restriction requirement	3-12-2008	sl

INTERFERENCE SEARCH			
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